

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10774577	COGGAN ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Dawn Garrett	1786

## SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
428	690, 917 (limited by text searching for all listed, see EAST search printout)	6-5-08	DG
313	504, 506 see EAST search history printout(s) in application file	6-5-08 through 10/2011	DG

## SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Inventor name search updated	6-5-08	DG
STIC structure search by EIC 1700 (see printout attached)	5-2008	DG
Updated EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	6-5-08	DG
See all prior search notes pages in application file		
Updated EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	12-3-08	DG
Updated EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	6-1-2009, 6-4-2009	DG
Updated EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	12-2-2009	DG
Reviewed STIC structure searches in application file	12-2-2009	DG
Updated EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	7-1-2010	DG
Updated EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	12-16-2010	DG
Updated EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	4-27-2011	DG
STN search - see printout	4-27-2011	DG
Updated EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	10-8-2011 AND 10-9-2011	DG

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>